Notice of References Cited Application/Control No. 10/756,763 Examiner Alexander O. Williams Applicant(s)/Patent Under Reexamination SUNOHARA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,250,843	10-1993	Eichelberger, Charles W.	257/692
*	В	US-2003/0178726 A1	09-2003	Ogawa et al.	257/758
*	С	US-6,919,226 B2	07-2005	Ogawa et al.	438/108
*	D	US-6,489,685	12-2002	Asahi et al.	257/774
*	Е	US-6,952,049	10-2005	Ogawa et al.	257/700
*	F	US-2005/0288392 A1	12-2005	Okubora, Akihiko	523/176
*	G	US-2004/0014317 A1	01-2004	Sakamoto et al.	438/689
*	Η	US-2006/0023439 A1	02-2006	Fraley et al.	361/780
*	1	US-6,822,170 B2	11-2004	Takeuchi et al.	174/258
*	J	US-6,038,133	03-2000	Nakatani et al.	361/760
*	К	US-6,538,210 B2	03-2003	Sugaya et al.	174/258
*	L	US-6,876,091 B2	04-2005	Takeuchi et al.	257/793
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2000-323645	11-2000	Japan	Takeuchi Yukuharu	
	0	2003-100937	04-2003	Japan	Kuriyama Satoru	
	Р	09-321439	12-1997	Japan	Noda Yuji	
	Q	2000-223837	08-2000	Japan	Hayashi Katsura	
	R	2002-170840	06-2002	Japan	O Touto	
	S					
	۲					

NON-PATENT DOCUMENTS

		NON TAILUT DOGGINENTO					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	٧						
	×						
	×						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.